

4/14/03
PATENT
81790.0189

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

MOMOHARA, Tomomi

Serial No: 09/686,200 (reissue of 08/718,660)

Filed: October 5, 2000

For: PROBE CARD HAVING GROUPS
OF PROBE NEEDLES IN A
PROBING TEST APPARATUS FOR
TESTING SEMICONDUCTOR
INTEGRATED CIRCUITS

Art Unit: 2829

Examiner: NGUYEN, Vinh P.

I hereby certify that this correspondence
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April 10, 2003

Date of Deposit

Michael Crapenchoff, Reg. No. 37,115

Name

Michael Crapenchoff April 10, 2003

Signature

Date

AMENDMENT

Commissioner for Patents
Washington, D.C. 20231

Dear Sir:

In response to the Office Action dated October 10, 2002, the time for response
to which is extended three months by the accompanying petition from January 10,
2003 to April 10, 2003, please amend the above-referenced reissue application as
follows:

IN THE CLAIMS:

Please replace the text of claims 6-11 with the following amended text:

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APR 10 2003

TECHNOLOGY CENTER 2800

6. (Amended) A method for testing semiconductor integrated
circuits, the method comprising:

providing a semiconductor wafer having a plurality of
semiconductor integrated circuit chips arranged thereon in two
columns and at least two rows, each of said plurality of semiconductor
integrated chips having a plurality of external terminals;